

EFFECT OF RANDOM VARIATIONS OF BOTH COMPOSITION AND THICKNESS OF 1D PHOTONIC CRYSTAL WITH ADMIXTURE PLASMA LAYERS ON PHOTONIC BAND GAP

Rumyantsev V.V.

A.A. Galkin Donetsk Institute for Physics and Engineering, NASU, s. Donetsk

Rumyantsev V.V.
A.A. Galkin Donetsk
Institute for Physics and
Engineering, NASU

Investigation of disorder effects in an imperfect superlattice allowing modeling the properties of photonic crystal containing the plasma layers is still of a great interest [1]. Development of the theory of photonic structures requires consideration of model systems such as photonic superlattice with plasma layers. Using the virtual crystal approximation [2] we study 1D-superlattice, which is a topologically ordered ensemble (such as a Si/liquid crystal or SiO₂/Si system) with randomly included admixture plasma layers. The superlattice is modeled as a set of macroscopically homogeneous layered system with randomly included extrinsic (with respect to the ideal superlattice) layers of variable composition and thickness. Corresponding configuration-dependent material tensors in our model [3] of the imperfect superlattice are represented in terms of random quantities. After configuration-averaging the translational symmetry of the considered system is "restored" that allows us obtain the system of equations which define normal modes of electromagnetic waves, propagating in one-dimensional "periodic" medium.

To specify the results, let's firstly consider the propagation of electromagnetic excitation in an imperfect Si/LC 1D superlattice with two elements (layers) in the cell, namely, with the first layer of silicon ($\varepsilon_1 = 11.7$) and the second layer of liquid crystal ($\varepsilon_2^{(1)} = 5.5$). Then we study SiO₂/Si 1D superlattice (with $\varepsilon_1 = 3.7$). The concentration, thickness and permittivity of the basic material layer in the first and second sublattices are denoted as $C_1^{(1)}$, $a_1^{(1)} = a_1$, $\varepsilon_1^{(1)} \equiv \varepsilon_1$ and $C_2^{(1)}$, $a_2^{(1)}$, $\varepsilon_2^{(1)} \equiv \varepsilon_2$, and the corresponding parameters of impurity layers with a different composition $C_{2C}^{(2)} \equiv C_C$ and thickness $C_{1T}^{(2)} \equiv C_T$, as well as $a_2^{(2)}$, $\varepsilon_2^{(2)}$. Note that the permittivity profile for inhomogeneous plasma is $\varepsilon_2^{(2)}(z) = 1 - \omega_e^2(z)/\omega^2$. For considered model plasma frequency is $\omega_e \ll \omega$ (collisions in plasma are neglected) and plasma density for $a_{n\alpha}$ -th layer varies exponentially:

$$n(z) = n_{cr} \left\{ \begin{array}{l} \exp \left[-\delta \left[z - (n-1)d - \sum_{j=1}^{\alpha} a_{nj} + a_{n\alpha} \right] / a_{n\alpha} \right] + \\ + \exp \left[-\delta \left(-z + (n-1)d + \sum_{j=1}^{\alpha} a_{nj} \right) / a_{n\alpha} \right] \end{array} \right\} / 2 \quad (1)$$

Gradation parameter δ corresponds to the volume average plasma permittivity $\langle \varepsilon_2^{(2)} \rangle = 0.9$. Below we are considered the case of admixture plasma layers only in LC-sublattice for Si/LC superlattice and in Si-sublattice for SiO₂/Si system. Simple calculations [4] yield the dependence the lowest photonic band gap width $\Delta\omega$ on plasma concentration of the systems studied:

$$\begin{aligned} \Delta\omega_1 / \omega &= (\varepsilon_1 - f_d f_{1C})^{-1} \sqrt{f_{1C}^2 f_{1T} + f_{2C} f_{2T} + f_{3C} f_{3T}}, \\ f_d &= a_2 [a_1 + a_2 + C_T (a_1^{(2)} - a_1)]^{-1}, f_{1T} = \pi^{-2} \text{Sin}^2 \pi f_d, \\ f_{2T} &= f_d \frac{\pi^{-1} \delta \text{Sin} 2\pi f_d + 4 f_d \text{Sin}^2 \pi f_d}{\delta^2 + (2\pi f_d)^2}, f_{3T} = f_d^2 \frac{\text{Sin}^2 \pi f_d}{\delta^2 + (2\pi f_d)^2}, \\ f_{1C}^2 &= [C_C (\varepsilon_2 - 1) + \varepsilon_1 - \varepsilon_2]^2, f_{2C} = C_C f_{1C}, f_{3C} \equiv C_C. \end{aligned} \quad (2)$$

The dependence $\Delta\omega(C_C, C_T)$ is shown in Fig. 1 for Si/LC superlattice and in Fig. 2 for SiO₂/Si system for different relative both composition and thickness of layers. Surface 1 in

Fig. 1 refers the case of $a_1/a_2 = 0.1$ and $a_1^{(2)}/a_2 = 0.5$, surface 2 corresponds to the case of $a_1/a_2 = 0.5$ and $a_1^{(2)}/a_2 = 0.1$. In Fig. 2 photonic band gap $\Delta\omega/\omega$ corresponds to the values $a_1^{(2)}/a_2$ and a_1/a_2 that are equal to 0,1; 10 (surface 1) and 10; 0,1(surface 2).

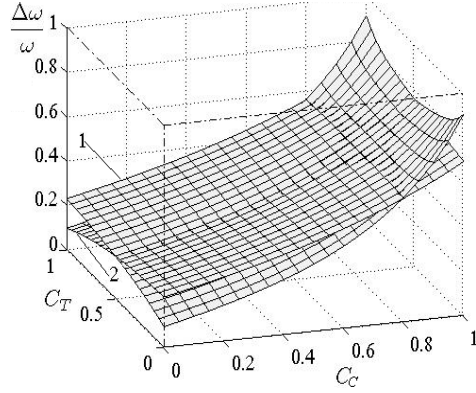


Fig. 1. Concentration dependence for a nonideal Si/LC 1D superlattice which contains plasma layers in LC-sublattice.

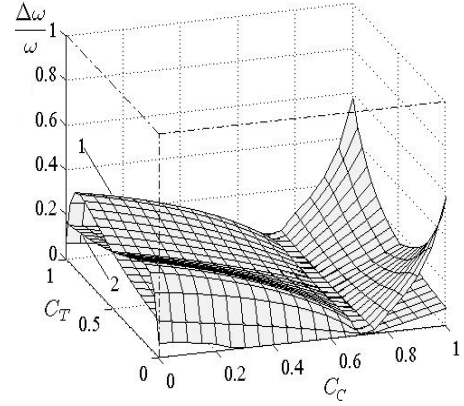


Fig. 2. Concentration dependence for a nonideal SiO₂/Si 1D superlattice which contains plasma layers in Si-sublattice.

Our results show that the optical characteristics of imperfect 1D superlattice may be significantly altered owing to transformation of their photon mode spectrum resulting a presence of admixture layers. Graphic representation $\Delta\omega(C_C, C_T)$ proves that the concentration dependence for the binary systems considered above differs for different relative composition of plasma layers. The case of nonideal multilayered systems with a larger number of sublattices and components of alien layers supposes a wide variety of specific behaviors of the photonic gap width. This circumstance extends considerably the promises of modeling composite materials with predetermined properties.

References

1. Xiang-kun Kong, Shao-bin Liu, Hai-feng Zhang, He-lan Guan. The effect of random variations of structure parameters on photonic band gaps of one-dimensional plasmas photonic crystal // Optics Communications. 2011. V. 284. No.12. P.2915-2918.
2. Parmenter R.H. Energy Levels of a Disordered Alloy// Phys. Rev. 1955. V. 97. P.587-698.
3. Rumyantsev V.V., Fedorov S.A., Gumennyk K.V. Peculiarities of band gap width dependence upon concentration of admixtures randomly included in 1D photonic crystal // Photonic Crystals: Optical Properties, Fabrication and Applications / ed. William L. Dahl, NY: Nova Science Publishers, Inc., 2011. P. 183-200.
4. Rumyantsev V.V., Fedorov S.A. Effect of random variations of both the composition and thickness on photonic band gap of one-dimensional plasma photonic crystal // Proceeding of PIERS 2012. The Electromagnetic Academy, 2012. P. 1411-1414